

Search Notes

Application/Control No.

10/530,943

Examiner

Jean F. Duverne

Applicant(s)/Patent under
Reexamination

TAN, WILLIAM

Art Unit

2839

SEARCHED

Class	Subclass	Date	Examiner
439	502	3/20/2006	JFD
	503		
	490		
	498		
	63		
	638		
	304		
362	236		
	249	3/20/2006	JFD
<i>updated 3/20/06 cc</i>			
<i>Search</i>			

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
<i>All above 3/20/06 cc</i>			
<i>+ See attachment</i>			

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR